UCC28251PW

Quality, reliability & packaging data download

Status: ACTIVE

Report date: 06/25/2024



Assembly site: TI MALAYSIA A/T

RoHS Yes

REACH Yes

Device marking UCC28251

Lead finish/Ball material NIPDAU

MSL rating/Peak reflow Level-1-260C-UNLIM

Rating Catalog



Material content

				Homogeneous I	Material Level	I Component Level	
Component	Substance	CAS Number	Amount (mg)	Percentage %	ppm	Percentage %	ppm
Bond Wire							
Copper and Its Alloys	Alloys Copper		0.116102	99.989665	999897	0.108821	1088
Copper and Its Alloys	Iron	7439-89-6	0.000001	0.000861	9	0.000001	0
Not Categorized	Proprietary Materials	_	0.000009	0.007751	78	0.000008	0
Precious Metals	Silver	7440-22-4	0.000002	0.001722	17	0.000002	0
Sub-total	_	_	0.116114	100	1000000	0.108832	1088
Die Attach Adhesive							
Precious Metals	Silver	7440-22-4	0.321688	80.000000	800000	0.301515	3015
Thermoplastics	Ероху	85954-11-6	0.080422	20.000000	200000	0.075379	754
Sub-total	_	_	0.402110	100	1000000	0.376893	3769
Lead Frame							
Copper and Its Alloys	Copper	7440-50-8	56.960365	97.584999	975850	53.388344	53388
Copper and Its Alloys	per and Its Alloys Iron		1.34251	2.300000	23000	1.258320	12583
Copper and Its Alloys	per and Its Alloys Phosphorus		0.008756	0.015001	150	0.008207	82
Zinc and Its Alloys	nc and Its Alloys Zinc		0.05837	0.100000	1000	0.054710	547
Sub-total	_	_	58.370001	100	1000000	54.709580	54709
Lead Frame Plating							
Nickel and Its Alloys	Nickel	7440-02-0	0.028536	95.120000	951200	0.026746	267
Precious Metals	Gold	7440-57-5	0.000234	0.780000	7800	0.000219	2
Precious Metals	Palladium	7440-05-3	0.00123	4.100000	41000	0.001153	12
Sub-total	_	_	0.030000	100	1000000	0.028119	281
Mold Compound							
Other Inorganic Materials	Fused Silica	60676-86-0	39.952474	86.000000	860000	37.447029	37447
Other Organic Materials	Carbon Black	1333-86-4	0.139369	0.300000	3000	0.130629	1306
Thermoplastics	Ероху	85954-11-6	6.364522	13.700000	137000	5.965399	59654
Sub-total	_	_	46.456365	100	1000000	43.543056	43543
Semiconductor Device							
Ceramics / Glass	Doped Silicon	7440-21-3	1.316049	100.000000	1000000	1.233519	12335
Sub-total	_	_	1.316049	100	1000000	1.233519	12335
Total	_	_	106.690639	_	_	100	10000



MTBF/FIT estimates

MTBF / FIT				MTBF / FIT supporting data					
MTBF	FIT	Usage temp (°C)	Conf level (%)	Activation energy (eV)	Test temp (°C)	Test duration (hours)	Sample size	Fails	Additional comments
9.999999999×10^9	0.1	55	60	0.7	125	1000	183306	0	_

Qualification summary

Stress	Reference	Min lot qty	SS / lot	Condition	Duration	Result	Notes
HTOL	JESD22-A108	3	77	Life test, 125C	1000 hours	Pass	Or equivalent JEDEC condition
HTSL	JESD22-A103	3	25	High temp storage bake, 150C	1000 hours	Pass	Or equivalent JEDEC condition
AC/UHAST	JESD22-A102/JESD22-A118	3	25	Unbiased HAST 130C / 85% RH	96 hours	Pass	Or equivalent JEDEC condition
THB/HAST	JESD22-A101/JESD22-A110	3	25	HAST 130C/85%RH	96 hours	Pass	Or equivalent JEDEC condition
TC	JESD22-A104	3	25	Temperature cycle -65/150C	500 cycles	Pass	Or equivalent JEDEC condition
SD	J-STD-002	3	22	Per specification	>95% lead coverage	Pass	_
НВМ	JS-001	1	3	ESD - HBM	Classification	See data sheet	_
CDM	JS-002	1	3	ESD - CDM	Classification	See data sheet	_
LU	JESD78	1	3	Latch-up	Per JESD78	Pass	As applicable per JESD78
MSL	J-STD-020	_	_	Per J-STD-020	Classification	See data sheet	_

Ongoing reliability monitoring

FAB process reliability data

Fab Process	Reliability Test	Rolling Year (2Q2023 - 1Q2024) Sample Size	Cumulative Sample Size	Disposition
Power BICMOS	Life test 125C, 1000 Hours or Equivalent JEDEC Condition	33096	398651	Pass

Assembly process reliability data

Package Family	Reliability Test	Rolling Year (2Q2023 - 1Q2024) Sample Size	Cumulative Sample Size	Disposition
TSSOP	Biased HAST 130C/85%RH, 96 Hours or Equivalent JEDEC Condition	2387	42385	Pass
TSSOP	High temp storage bake 150C, 1000 Hours or Equivalent JEDEC Condition	1330	32206	Pass
TSSOP	Temperature cycle -65/150C, 500 Hours or Equivalent JEDEC Condition	7700	89445	Pass
TSSOP	Unbiased HAST 130C/85% RH, 96 Hours or Equivalent JEDEC Condition	5621	72531	Pass



Additional resources

General quality guidelines

Certifications

Conflict minerals specialized disclosure report

Restricted chemical test report

For additional component information, please visit Material content search

For additional information, please contact TI customer support center

Important Notice and Disclaimer

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.